Se	arch Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/622,733	LU ET AL.
Examiner	Art Unit
Nhan T. Tran	2622

SEARCHED				
Class	Subclass	Date	Examiner	
348	297	10/6/2006	NT	

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST search (USPAT, PGPUB, JPO, EPO, DERWENT, IBM_TDB) text search - see search history printout	10/6/2006	NT	
348/294-299 (text search - see search history printout)	10/9/2006	NT	
348/229.1, 294-324, 362 (text search - see search history printout)	10/10/2006	NT	
Inventorship search - see search history printout	10/13/2006	NT	